Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/616,525	FUNK ET AL.	
Examiner	Art Unit	
J. Derek Rutten	2192	

	SEARCHED					
Class	Subclass	Date	Examiner			
		-				
	141					
	-					
			-			

· INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
<u></u>		-			

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
PLUS database search EAST (US-PGPUB; USPAT; EPO; JPO; IBM_TDB; DERWENT) - see search history printout	11/21/2006	JDR
Inventor Name search Rosenberg, "How Debuggers Work"	11/21/2006	JDR
717/129 - text search only See search history printout	11/21/2006	JDR
EAST (US-PGPUB; USPAT; EPO; JPO; IBM_TDB; DERWENT) - see search history printout	11/22/2006	JDR
717/127-130; 714/34,35 Text search only See search history printout	11/22/2006	JDR
Google - www.google.com ACM - www.acm.org See search history printout	11/22/2006	JDR
Tuan Dam (consulted re. 112 1st)	11/28/2006	JDR